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R. Assalti, R. T. Doria, D. Flandre and M.Souza

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F. D. V. R. Oliveira, T. M. F. Lopes, J. G. R. C. Gomes, F. A. P. Barúqui and A. Petraglia

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CONTENTS

Foreword *05*

Origin of the Low-Frequency Noise in the Asymmetric Self-Cascode Structure Composed by Fully Depleted SOI nMOSFETs

Rafael Assalti, Rodrigo Trevisoli Doria, Denis Flandre and Michelly de Souza 07

Focal-Plane Compression Imager with Increased Quantization Bit Rate and DPCM Error Modeling

Fernanda Duarte Vilela Reis de Oliveira, Tiago Monnerat de Faria Lopes, José Gabriel Rodríguez Carneiro Gomes, Fernando Antônio Pinto Barúqui and Antonio Petraglia 16

Ground Plane Influence on Analog Parameters of Different UTBB nMOSFET Technologies

V. T. Itocazu, V. Sonnenberg, J.A. Martino, E. Simoen and C. Claeys.....27

Electrospun Polymeric Fibers Coated With Pd As A Sensitive Layer For Hydrogen Detection

Ana Neilde R. da Silva, Sebastião G. dos Santos Filho, Marcelo Bariatto A. Fontes 34

An UHF RFID tag characterization methodology including a low-cost and low-complexity SDR platform for information extraction

Juan Sebastián Moya Baquero, Fabian L. Cabrera and Fernando Rangel de Sousa 40

Analytical Model for Threshold Voltage in UTBB SOI MOSFET in Dynamic Threshold Voltage Operation

V. T. Itocazu, K. R. A. Sasaki, V. Sonnenberg, J.A. Martino, E. Simoen and C. Claeys..47

FOREWORD

This issue continues the publication of selected papers from those presented at SBMicro2016 (31th Symposium on Microelectronics Technology and Devices) and SBCCI2016 (29th Symposium on Integrated Circuits and Systems Design), which have been held in Belo Horizonte, Brazil, in 2016. Among the contributions presented at both Symposia, only a few best rated were selected by the JICS Editorial Board and have been invited to submit an extended version to the Journal. These extended papers have passed through the usual reviewing process before acceptance.

In addition to the best papers presented at these conference, spontaneous submissions passed through the usual reviewing process and have been accepted as regular papers.

We would like to thank the authors for their effort in preparing these high quality papers, as well as the reviewers for their valuable contribution on paper evaluation and selection, which guarantees the scientific level of this issue. We sincerely hope that JICS readers will enjoy these contributions.

Marcelo Antonio Pavanello
JICS Editor-in-chief